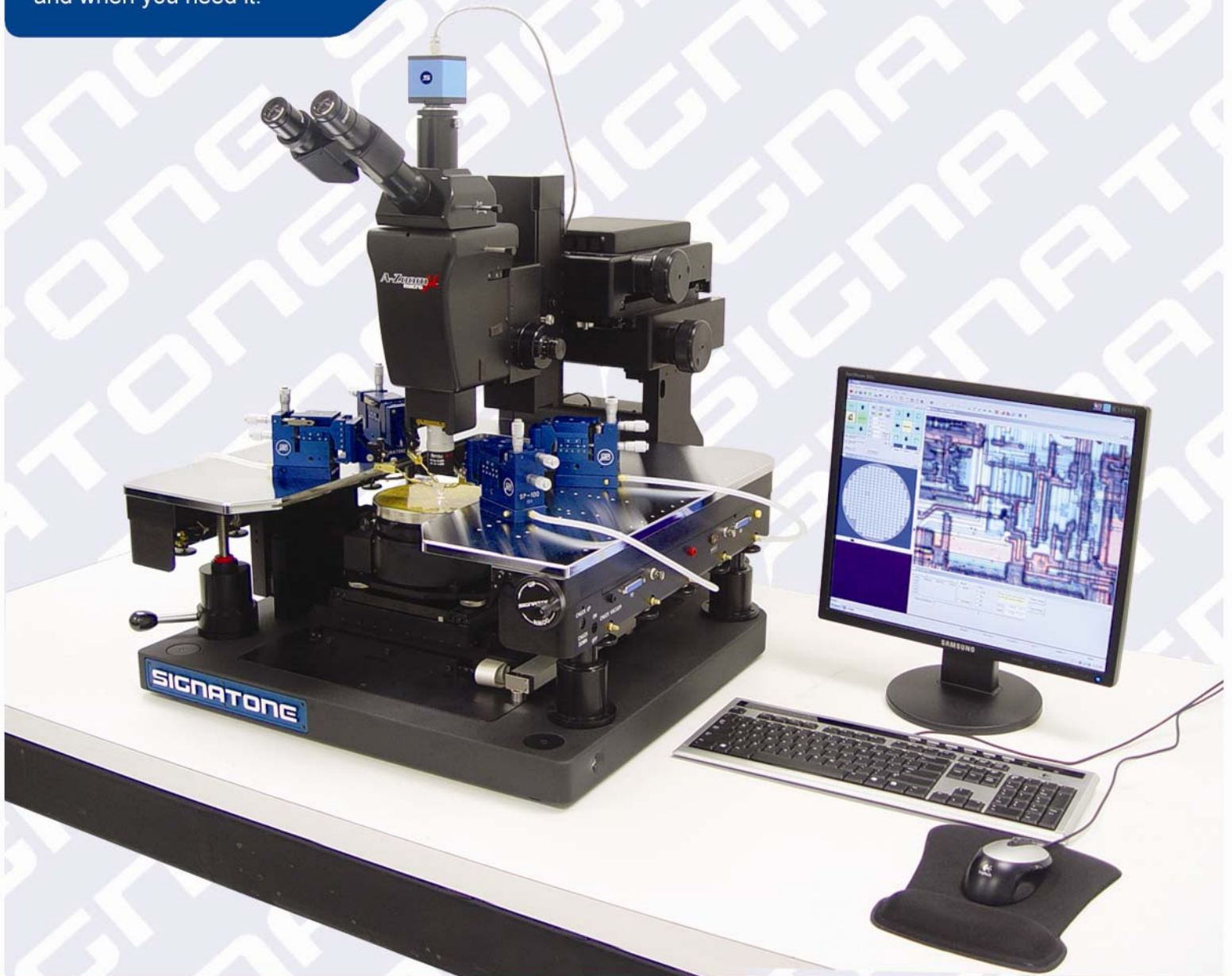


CM-460 SERIES



150mm Semi-Automatic Probe Station

The perennial workhorse in the SIGNATONE product offering, the CM-460 Series of 6" semi-automatic analytical probe stations represents mature technology at its best. Based on our proven linear motor technology, which virtually eliminates accuracy and repeatability issues, the CM-460 will deliver years of worry-free performance where and when you need it.



PERFORMANCE, QUALITY, VALUE

SIGNATONE®

Advanced Microprobing Solutions Since 1968

CM-460 SERIES



Specifications

- ◆ 150mm linear motor drive
- ◆ 2-Point software alignment
- ◆ Software Z control
- ◆ 2" & 6" manual/programmable/hybrid microscope transports available
- ◆ Optional 4" microscope lift
- ◆ Chuck X-Y Resolution: $.1\mu$ (1μ S-465)
- ◆ Chuck X-Y Repeatability: $.5\mu$ (1μ S-465)
- ◆ Chuck X-Y Accuracy: 1μ (3μ S-465)
- ◆ Chuck Z Resolution: $.1\mu$
- ◆ Chuck Z Accuracy: $.25\mu$
- ◆ Chuck Θ : 18 degrees

X-Y Motion Control

- ◆ "Point & Shoot" movements
- ◆ 8 directional arrows with variable speed control
- ◆ Wafer map "Pick & Move"
- ◆ "Go To" commands

Z Motion Control

- ◆ Separate contact/overdrive height
- ◆ Z motion speed control
- ◆ Safety lock
- ◆ Soft Z with edge sense circuit (for use w/probe card edge sense)

User-Friendly Features

- ◆ Stores setup and programs for easy retrieval
- ◆ Icons for most applications
- ◆ Basic Run mode guides the user through basic operations
- ◆ On-Screen video display option
- ◆ Wafer map position indicator

Integrated Probing Solutions For Testing

- ◆ CV
- ◆ Vth
- ◆ Tox
- ◆ IV
- ◆ Sub-Threshold
- ◆ Leakage to 5 fA
- ◆ Resistivity
- ◆ WLR
- ◆ Dark Current
- ◆ Pulse mode 10A/100V Measurements

Programming

- ◆ Wafer Map design editor
- ◆ Selective programming
- ◆ Learn position
- ◆ Subroutine with chuck or Computer aided Probe

Interfacing

- ◆ DDE interface integrated with ICS Metrics for instrument control of most Keithley and Agilent instruments
- ◆ Application SW for Keithley 2400 Series
- ◆ DDE compatible with HP VEE
- ◆ DDE compatible with NI LABView
- ◆ GPIB compatible with NI LABView

Other Features

- ◆ Microscope X-Y-Z and Zoom control
- ◆ Color wafer bin mapping with 16 colors
- ◆ Hot chuck interface and control
- ◆ Accepts probe cards
- ◆ Available vibration isolation tables
- ◆ Optional Controller/Instrumentation rack

ICS-Metrics Software

- ◆ ICS-Metrics integrates Agilent and Keithley DC/CV instrumentation for the automated characterization of semiconductor parameters
- ◆ Graphical user interface for all instrument functions
- ◆ Simple, pre-configured test formats for semiconductor devices
- ◆ Data collection and storage
- ◆ Sequential test execution
- ◆ Data analysis and reporting

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